

INTERNATIONAL STANDARD



Metallic ~~communication~~ cables and other passive components test methods – Part 4-7: Electromagnetic compatibility (EMC) – Test method for measuring of transfer impedance Z_T and screening attenuation a_S or coupling attenuation a_C of connectors and assemblies ~~up to and above 3 GHz~~ – Triaxial tube in tube method

IEC 62153-4-7:2021

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**METALLIC ~~COMMUNICATION~~ CABLES AND OTHER PASSIVE
COMPONENTS TEST METHODS –****Part 4-7: Electromagnetic compatibility (EMC) –
Test method for measuring of transfer impedance Z_T and screening
attenuation a_S or coupling attenuation a_C of connectors and assemblies
~~up to and above 3 GHz~~ – Triaxial tube in tube method**

FOREWORD

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IEC 62153-4-7 has been prepared by IEC technical committee 46: Cables, wires, waveguides, RF connectors, RF and microwave passive components and accessories. It is an International Standard.

This third edition cancels and replaces the second edition published in 2015 and its Amendment 1:2018. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

The document is revised and updated. It now includes IEC 62153-4-7:2015/COR1:2016 and IEC 62153-4-7:2015/AMD1:2018. Furthermore, the changes of the revised IEC 62153-4-9:2018 are included.

Measurements of the coupling attenuation can be achieved now by using a mixed mode network analyser (virtual balun). The following new annexes have been added:

- Annex E contains informative information about the direct measurement of screening effectiveness of connectors;
- Annex F gives normative information about mixed mode parameters;
- Annex G contains normative information about accessories for measuring coupling attenuation;
- Annex H discusses the low frequency screening attenuation.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
46/812/FDIS	46/820/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

A list of all parts of the IEC 62153 series, under the general title *Metallic cables and other passive components test methods* can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
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INTRODUCTION

The shielded screening attenuation test set-up according to IEC 62153-4-3 and IEC 62153-4-4 have been extended to take into account the particularities of electrically short elements like connectors and cable assemblies. Due to the concentric outer tube of the triaxial set-up, measurements are independent of irregularities on the circumference and outer electromagnetic fields.

With the use of an additional resonator tube (inner tube respectively tube in tube), a system is created where the screening effectiveness of an electrically short device is measured in realistic and controlled conditions. Also, a lower cut off frequency for the transition between electrically short (transfer impedance Z_T) and electrically long (screening attenuation a_S) can be achieved.

A wide dynamic and frequency range can be applied to test even super screened connectors and assemblies with normal instrumentation from low frequencies up to the limit of defined transversal waves in the outer circuit at approximately 4 GHz.

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METALLIC ~~COMMUNICATION~~ CABLES AND OTHER PASSIVE COMPONENTS TEST METHODS –

Part 4-7: Electromagnetic compatibility (EMC) – Test method for measuring of transfer impedance Z_T and screening attenuation a_S or coupling attenuation a_C of connectors and assemblies ~~up to and above 3 GHz~~ – Triaxial tube in tube method

1 Scope

This part of IEC 62153 deals with the triaxial tube in tube method. This triaxial method is suitable to determine the surface transfer impedance and/or screening attenuation and coupling attenuation of mated screened connectors (including the connection between cable and connector) and cable assemblies. This method could also be extended to determine the transfer impedance, coupling or screening attenuation of balanced or multipin connectors and multicore cable assemblies. For the measurement of transfer impedance and screening- or coupling attenuation, only one test set-up is needed.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC TS 62153-4-1:2014, *Metallic communication cable test methods – Part 4-1: Electromagnetic compatibility (EMC) – Introduction to electromagnetic screening measurements*

IEC 62153-4-3, *Metallic communication cable test methods – Part 4-3: Electromagnetic Compatibility (EMC) – Surface transfer impedance – Triaxial method*

IEC 62153-4-4, *Metallic communication cable test methods – Part 4-4: Electromagnetic compatibility (EMC) – ~~Shielded screening attenuation~~, Test method for measuring of the screening attenuation as up to and above 3 GHz, triaxial method*

IEC 62153-4-8, *Metallic cables and other passive components – Test methods – Part 4-8: Electromagnetic compatibility (EMC) – Capacitive coupling admittance*

IEC 62153-4-9:2018, *Metallic communication cable test methods – Part 4-9: Electromagnetic compatibility (EMC) – Coupling attenuation of screened balanced cables, triaxial method*

IEC 62153-4-10, *Metallic communication cable test methods – Part 4-10: Electromagnetic compatibility (EMC) – Transfer impedance and screening attenuation of feed-throughs and electromagnetic gaskets - Double coaxial test method*

IEC 62153-4-15:2015, *Metallic communication cable test methods – Part 4-15: Electromagnetic compatibility (EMC) – Test method for measuring transfer impedance and screening attenuation – or coupling attenuation with triaxial cell*

IEC 62153-4-16, *Metallic communication cable test methods – Part 4-16: Electromagnetic compatibility (EMC) – Extension of the frequency range to higher frequencies for transfer impedance and to lower frequencies for screening attenuation measurements using the triaxial set-up*

EN 50117-9-2:2019, *Coaxial cables – Part 9-2: Sectional specification for coaxial cables for analogue and digital transmission – Indoor droop cables for systems operating at 5 MHz – 3 000 MHz*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1

surface transfer impedance

Z_T

for an electrically short screen, quotient of the longitudinal voltage U_1 induced to the inner circuit by the current I_2 fed into the outer circuit or vice versa

Note 1 to entry: The surface transfer impedance is expressed in ohms.

Note 2 to entry: The value Z_T of an electrically short screen is expressed in ohms [Ω] or decibels in relation to 1 Ω .

Note 3 to entry: See Figure 1.

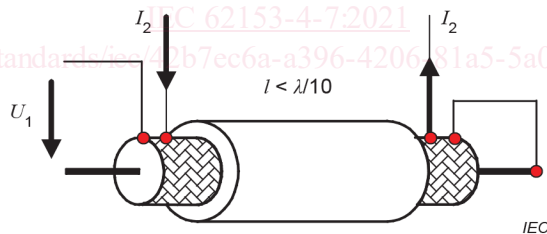


Figure 1 – Definition of Z_T

$$Z_T = \frac{U_1}{I_2} \quad (1)$$

$$Z_T \text{ dB}(\Omega) = +20 \times \log_{10} \left(\frac{|Z_T|}{1 \Omega} \right) \quad (2)$$

3.2

effective transfer impedance

Z_{TE}

~~effective transfer impedance, defined as:~~

maximum absolute value of the sum or difference of the capacitive coupling impedance Z_F and the transfer impedance Z_T at every frequency:

$$Z_{TE} = \max |Z_F \pm Z_T| \quad (3)$$

3.3 screening attenuation

a_S
for electrically long devices, i.e. above the cut-off frequency, logarithmic ratio of the feeding power P_1 and the periodic maximum values of the coupled power $P_{r,max}$ in the outer circuit

$$a_S = -10 \times \log_{10} \left(\text{Env} \left| \frac{P_{r,max}}{P_1} \right| \right) \quad (4)$$

where

~~Env is the minimum envelope curve of the measured values in dB~~

Note 1 to entry: The screening attenuation of an electrically short device is defined as:

$$a_S = 20 \times \log_{10} \frac{150 \Omega}{Z_{TE}} \quad (5)$$

where

150 Ω is the standardized impedance of the outer circuit.

3.4 coupling attenuation

a_C
for a screened balanced device, the sum of the unbalance attenuation a_U of the symmetric pair and the screening attenuation a_S of the screen of the device under test

Note 1 to entry: For electrically long devices, i.e. above the cut-off frequency, the coupling attenuation a_C is defined as the logarithmic ratio of the feeding power P_1 and the periodic maximum values of the coupled power $P_{r,max}$ in the outer circuit.

3.5 coupling length

~~length of cable inside the test jig between the end of the extension tube and the screening cap (see Figure 2)~~

length of device under test

Note 1 to entry: The coupling length is electrically short, if

$$\frac{\lambda_o}{l} > 10 \times \sqrt{\epsilon_{r1}} \quad \text{or} \quad f < \frac{c_o}{10 \times l \times \sqrt{\epsilon_{r1}}} \quad (6)$$

or electrically long, if

$$\frac{\lambda_o}{l} \leq 2 \cdot \left| \sqrt{\epsilon_{r1}} - \sqrt{\epsilon_{r2}} \right| \quad \text{or} \quad f > \frac{c_o}{2 \cdot l \cdot \left| \sqrt{\epsilon_{r1}} - \sqrt{\epsilon_{r2}} \right|} \quad (7)$$

$$\frac{\lambda_o}{l} \leq \pi \times \left| \sqrt{\epsilon_{r1}} \pm \sqrt{\epsilon_{r2}} \right| \quad \text{or} \quad f \geq \frac{c_o}{\pi \times l \times \left| \sqrt{\epsilon_{r1}} \pm \sqrt{\epsilon_{r2}} \right|} \quad (7)$$

where